

Application/Contro	λĪ	No.
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10/541,327

SHIMIZU ET AL.

Examiner

2834

Applicant(s)/Patent under

Reexamination

Nguyen N. Hanh

SEARCHED				
Class	Subclass	Date	Examiner	
310	156.01- 156.84	6/20/2006	НИ	
310	261	6/20/2006	HN	
310	262	6/20/2006	HN	
310	218	6/20/2006	HN	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
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